

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1096	((semiconductor or silicon or si) same (ferroelectric)) and (tip or probe)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:40
L2	2243	(leak\$3 near3 current) same (probe or tip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:40
L3	15	L1 and L2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:40
L4	1161	369/126.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:43
L5	25	L1 and L4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:43
L6	233	365/151.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:43
L7	30525	(probe near5 tip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:43
L8	35	L7 and L6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:43
L9	11697	(block or bulk) near2 eras\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:44

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L10	1161	369/126.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:44
L11	22	L9 and L10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:44
L12	4	US-5557596-\$.DID. OR US-5418029-\$.DID.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L13	10	US-5371729-\$.DID. OR US-6064587-\$.DID. OR US-5835477-\$.DID. OR US-4731754-\$.DID. OR US-2922986-\$.DID.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L14	1161	369/126.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L15	2371	365/145.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L16	202450	ferro\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L17	60	L16 same L7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L18	3742	L14 or L6 or L15	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L19	2	L17 and L18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45

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L20	1161	369/126.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L21	341	369/101.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L22	1381	L20 or L21	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L23	9	L2 and L22	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:45
L24	1	10/698717	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2008/02/15 19:46
L25	0	((probe or tip) near5 (semiconductor) near6 (poled near2 ferroelectric) same (electrical) same (multiple near2 bit\$1)).clm.	US-PGPUB	OR	ON	2008/02/15 19:49